PRODUCT SPECIFICATION

[1. SCOPE]

This specification defines the performance for the microSD + nano SIM + nano SIM 3in3 Combination Socket Stacked, Pin-Eject Type with Tray series.

[2. PRODUCT NAME AND PART NUMBER]

Product Name	Part Number		
Product Name	Socket	Embossed package	
mSD/nSIM 3in3 Stacked Socket, Pin-Eject Type with Tray (with 2 DIP Length 0.45mm)	201458-1114	201458-1114	

[3. RATINGS]

Item	Standar	ď	
Rated Voltage (MAX.)	10 Volts		
Rated Current (MAX.)	0.5 Amps	AC(RMS) or DC	
Operating temperature Rating	-40°C ~ +85°C *1		
Storage temperature Rating	-40°C ~ +85°C *1		
Relative humidity	10% to 80% R.H *2		

*1 : Including terminal temperature rise.

*2 : Storage area is to be free of corrosive gases and dew formation.

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	DESIGN CONTROL STATUS KOR M			ITTEN BY: (ANG			APPROVED BY: SH.CHU	DATE: YR/MO/D 2020/09/02				
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[4. PERFORMANCE]

4-1. Electrical Performance

Item		Test Condition	Requirement				
				100 mΩ MAX.			
4-1-1	Contact Resistance	Mate dummy card *, measure by dry circuit, 20mV MAX., 10mA MAX. (IEC 60512-2-1 / JIS C 5402 5.4)	nSIM	100 mΩ MAX.			
			Detector ~ Switch	200 mΩ MAX			
4-1-2	Insulation Resistance	Apply 500V DC between adjacent pins or pin and ground. (MIL-STD-202, Method 302)	1000 MΩ MIN.				
4-1-3	Dielectric Strength	Apply 500V AC for 1 minute between adjacent terminals and ground. (MIL-STD-202, Method 301)	No Breakdown				
L	* The dummy card shows the card for the evaluation made of our company						

4-2. Mechanical Performance

	ltem	Test Condition	Requirement	
4-2-1	Tray Inse r tion Force	Push the Tray at the speed rate of 25±3 mm / minute. (with actual cards)	Insertion force	10 N MAX. {1.0 kgf MAX.}
4-2-2	Pin Ejection Force	Push the Eject-Bar using a pin.(25mm/min) with actual cards on a Tray. Measure the force at the 3rd.	Push force	4N ~13N {0.4Kgf ~ 1.3kgf}

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422	Duch Strongth	The Tray is inserted in positive direction and the load of 19.6 N {2 kgf} is added for 20 seconds at the speed rate of 25±3 mm / minute	Appearance	No mechanical damage
4-2-3	Push Strength	Force the entrance of socket in positive direction at the speed rate of 25±3 mm / minute	Peeling force From PCB	100 N MIN. {10 kgf MIN.}
4-2-4	Contact Normal Force	Measure contact normal force at the speed rate of 25±3 mm / minute. ** The amount of deflection of the contact terminal should include the protrusion of the	microSD	Initial : 0.30N MIN./PIN {0.03kgf Min}
		bead at the bottom of the Shell from the terminal contact point. ** Thickness of cards are 0.67mm for nanoSIM card and 0.70mm for microSD card.	nanoSIM	Initial : 0.35N MIN./PIN {0.035kgf Min}
4-2-5	Eject-Bar	Measure the strength at the speed rate of 25±3 mm / minute for 3 secs, at less than 1.60mm; the working distance of the Eject-bar. Apply force to the Eject-bar while holding the tray handle firmly ** Cards are inserted		40N MIN {4 kgf MIN}
4-2-5	Strength	Tray fixed	Appearance	No remarkable damage on ejecting mechanism.

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		Tray(with actual cards to 2,000 cycles.) insertion and removal up			
		Measure contact heigh surface to contact top and after test.	t (from Housing top point) difference before			
		Air blow Jig and Conta at each 50 cycle inter	acts (dry air) for 3 secs : val.			
4-2-6	Contact Deformation			Plastic deformation	MAX. Cha From Initial height 20%	contact
		** Results may be obt test item(4-3-1).	ained from the durability			
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4-3. Environmental Performance and Others

	Item	Test Condition	Requirement		
		Before the full-scale test, the first 5 times insert / take out an empty tray(without any cards) by hand using the tray handle portion directly.	Contact Resistance	MAX. Change From Initial contact resistance 40mΩ MAX. after 2,000cycles.	
4-3-1	Durability (Life cycle)	Insertion and extraction are repeated 6 ~ 2,000 cycles with test PCB dummy card by Eject-Pin mechanism. After 2,000 cycles, clean a tray hook, air blow card & socket (dry air) for 10 secs. When mesuring at the 2,000 cycles, it need to change to a new Tray. This is to avoid deformation of the Tray itself.	Pin Ejection Force	4N ~13N {0.4Kgf ~ 1.3kgf} after 2,000cycles	
		 And Air blow Socket (dry air) for 10 secs. * Thickness of all test PCB dummy cards are 0.57~0.64mm. * Test speed rate: 20~40/min. 	Appearance	No remarkable damage on ejecting mechanism.	
4-3-2	Temperature Rise	Carrying rated current load (UL 498 / IEC 60512-5-1)		30 °C MAX.	

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			Mate dummy card and subject to the following vibration conditions, for a period of 2 hours in each of 3 mutually	Appearance	Appearance, construction: No defect such as remarkable abrasion, breakage or crack on the component.
	4-3-3	Vibration	perpendicular axes, passing DC 1 mA during the test. Amplitude: 1.52 mm P-P Frequency: 10-55-10 Hz Shall be traversed in 1 minute.	Contact Resistance	MAX. Change From Initial contact resistance 40mΩ MAX.
			(MIL STD-202, Method 201)	Discontinuity	1.0 micro sec. MAX.
	4-3-4	Shock	Mate dummy card and subject to the following shock conditions. 3 shocks shall be applied along 3 mutually perpendicular axes(+/- X, Y, Z), passing DC 1mA current during the test. (Total of 18 Shocks) Test pulse: Half Sine Peak value: 50G(490m/s ²) Duration: 11 ms (MIL-STD-202 Method 213)	Appearance	Appearance, construction: No defect such as remarkable abrasion, breakage or crack on the component.
				Contact Resistance	MAX. Change From Initial contact resistance 40mΩ MAX.
				Discontinuity	1.0 microsec. MAX.
			Mate dummy card and exposed to $40\pm2^{\circ}$ C, relative humidity 90~95% chamber for 96 hours.	Appearance	Appearance, construction: No defect such as remarkable abrasion, breakage or crack on the component.
	4-3-5	Moisture resistance	Upon completion of the exposure period, the test specimens shall be conditions at ambient room conditions for 1 to 2 hours, after which the specified measurements shall be performed. (IEC-60512-11-3)	Contact Resistance	MAX. Change From Initial contact resistance 40mΩ MAX.
				Dielectric Strength	Must meet 4-1-3

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				Insulation Resistance	100 MΩ MIN.
	4-3-6	Temperature cycling	Mate dummy card and subject to the following conditions for 5 cycles. Upon completion of the exposure period, the test specimens shall be conditioned at ambient room conditions for 1 to 2 hours, after which the specified measurements shall be performed. 1 cycle	Appearance	Appearance, construction: No defect such as remarkable abrasion, breakage or crack on the component.
			 a) -40±3°C · · · 2 hours b) +85±2°C · · · 2 hours Transit time shall be within 3 minutes. (EIA-364-32C / IEC 60512-11-4) 	Contact Resistance	MAX. Change From Initial contact resistance 40mΩ MAX.
		Heat Resistance Heat Resistance	Upon completion of the exposure period, the test	Appearance	Appearance, construction: No defect such as remarkable abrasion, breakage or crack on the component.
4-3-7	4-0-7		conditions for 1 to 2 hours, after which the specified measurements shall be performed.	Contact Resistance	MAX. Change From Initial contact resistance 40mΩ MAX.
	4-3-8	B Cold Resistance	conciment chall be conditione at ambient room	Appearance	Appearance, construction: No defect such as remarkable abrasion, breakage or crack on the component.
		conditions for 1 to 2 hours, after which the specified measurements shall be performed. (IEC 60512-11-10)	Contact Resistance	MAX. Change From Initial contact resistance 40mΩ MAX.	

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	Item	Test Condition	Requirement		
4-3-9	20.0	Mate dummy card and expose to 50 ± 5 ppm SO ₂ gas, ambient temperature $40\pm2^{\circ}$ C, relative humidity 75% for 24 hours.		Appearance, construction: No defect such as remarkable abrasion, breakage or crack on the component.	
	SO2 Gas	** Dummy card must be assured same test separately, otherwise use the new dummy card to measure the change of contact resistance.	Contact Resistance	MAX. Change From Initial contact resistance 40mΩ MAX.	
4-3-10	Appearance at mist conditions. Upon completion of the exposure period, salt deposits shall be removed by a gentle wash or dip in running water, and air blow(dry air) for 3 seconds. The test specimens shall be dry for 1 to 2 hours at ambient room temperature after which the ambient room temperature after which the	salt mist conditions. Upon completion of the exposure period, salt deposits shall be removed by a gentle wash or dip in running water, and air blow(dry air) for 3	Appearance	Appearance, construction: No defect such as remarkable abrasion, breakage or crack on the component.	
		MAX. Change From Initial contact resistance 40mΩ MAX.			
		separately, otherwise use the new dummy card		100 MΩ MIN.	
4-3-11	Solderability	Dip solder tails into the molten solder (held at 245 \pm 5°C) up to 0.5mm from the tip of tails for 3±0.5 sec. (JIS C60068-2-20 4.6)	Solder Wetting	90% of immersed area must show no voids, Pinholes	

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4-3-12	Thermal shock	Mate dummy card and subject to the follo conditions for 96 cycles. Upon completion exposure period, the test specimens sha conditioned at ambient room conditions for hours, after which the specified measure shall be performed. 1 cycle a) -40±3°C · · · 30 minutes b) +85±2°C · · · 30 minutes Transit time shall be within 5 minutes.	n of the I be or 1 to 2	abrasion, breakage or crack on the component. MAX. Change From Initial contact	
			Insulation Resistance	100 Μ Ω	
	Temperature and Humidity	Mate dummy card and expose to ambient temperature 85±2°C, relative humidity 85% for 120 hours. The test specimens shall be condit ambient room conditions for 1 to 2 hours	Appearanc	Appearance, construction: No defect such as remarkable abrasion, breakage or crack on the component.	
4-3-13		** Dummy card must be assured same test separately, otherwise use the new dummy card to	y card to	Max. Change From Initial contact resistance 40mΩ MAX.	
		measure the change of contact resistanc	e. Insulation Resistance		
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4-3-14 Resistance to soldering heat 4-3-14 Resistance to solder temperature 4-3-14 Resistance to soldering heat 4-3-14 Resistance to solder temperature 4-3-14 Researce to solder temperature 4-3-15 Researce to the terminal. Recommend the reflow soldering only, do not manual soldering as possible.
** (): Reference Standard

[5. PRODUCT SHAPE, DIMENSIONS]

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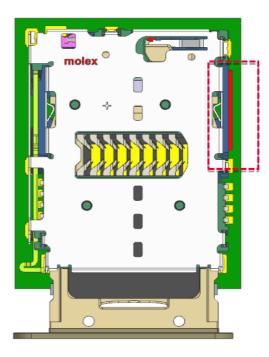


Item	Test Method	Specifications
Appearance	Visual Inspection	No rust, contamination, Damage nor deformation Effecting on function
Appearance Dimension		Refer to drawings.

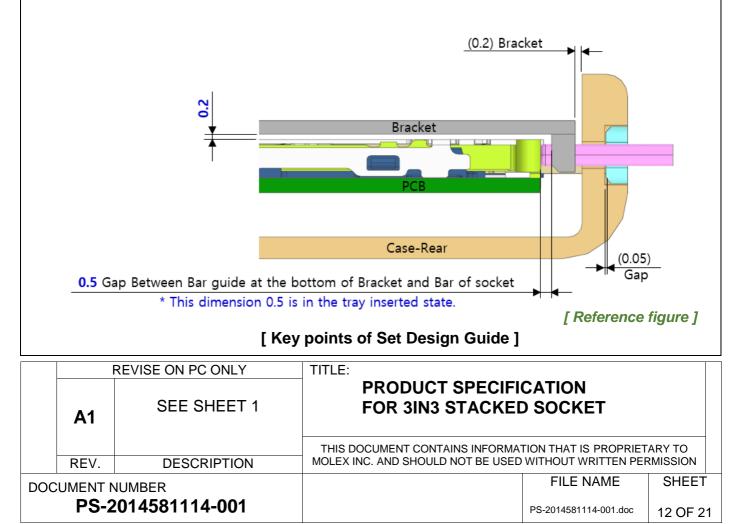
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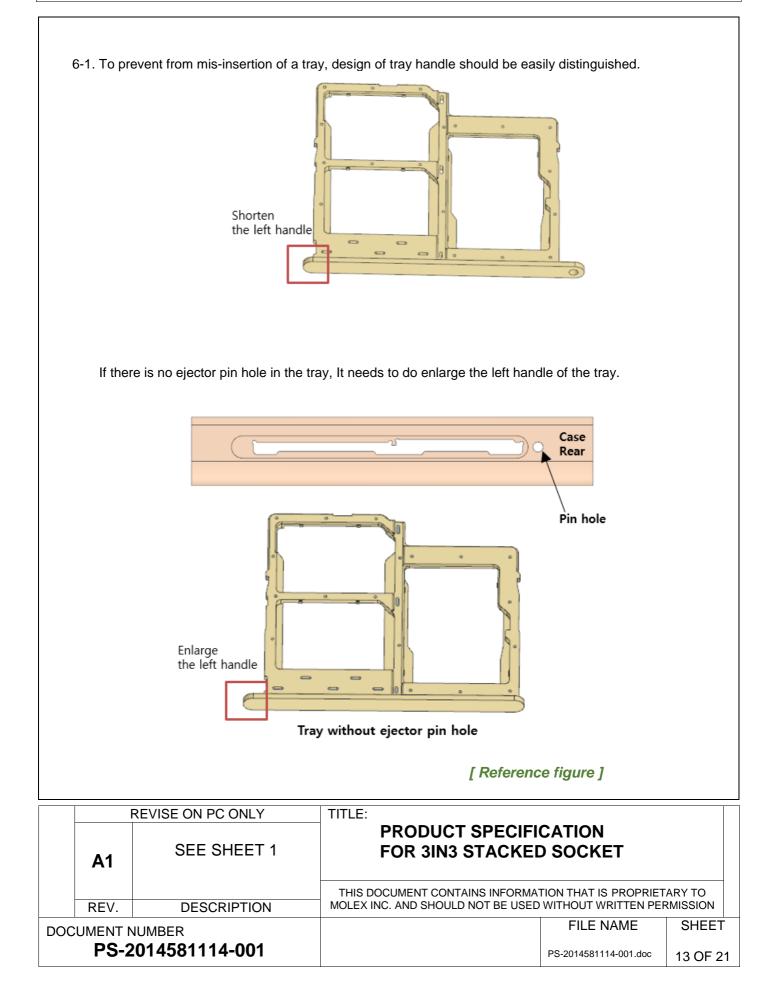


[6. RECOMMENDED DESIGN GUIDE FOR APPLICATION]



** For detail demension, please refer to 2D drawing.







6-2. Card stuck prevention

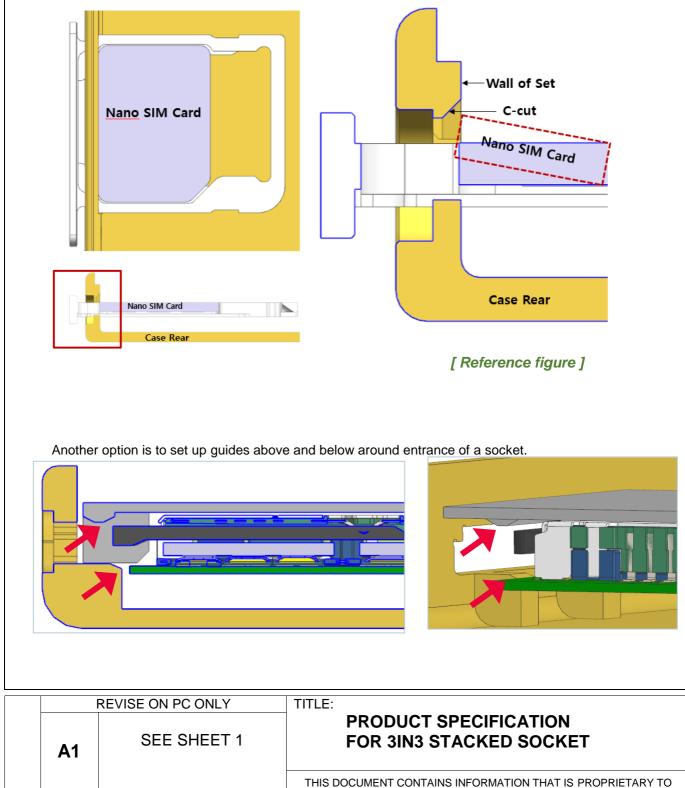
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To avoid the nanoSIM or microSD card stuck, pop-up to the inner entrance of set case, add the C-cut shape on the inner wall of set case.



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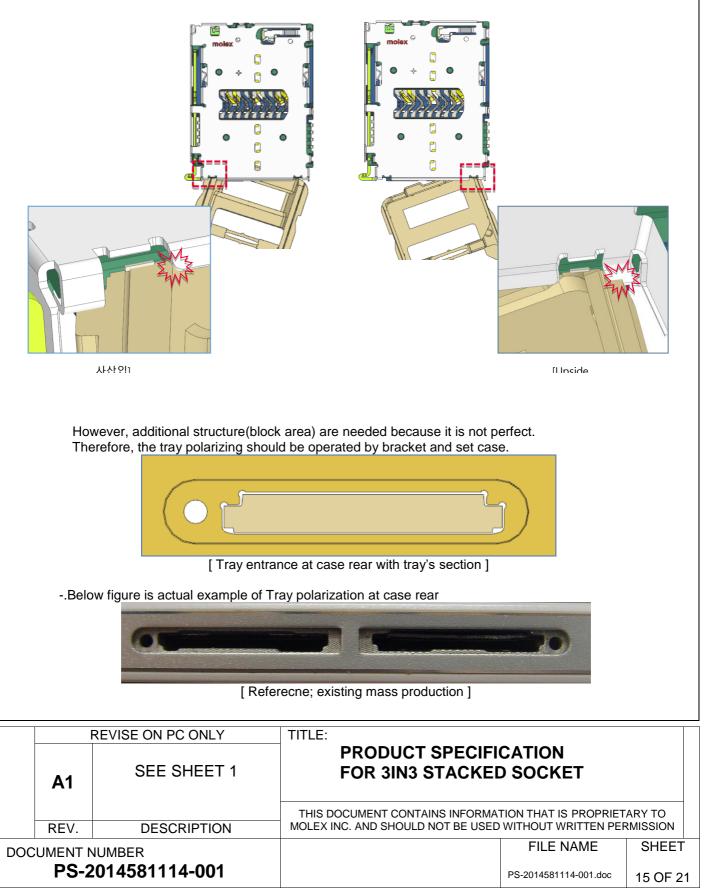
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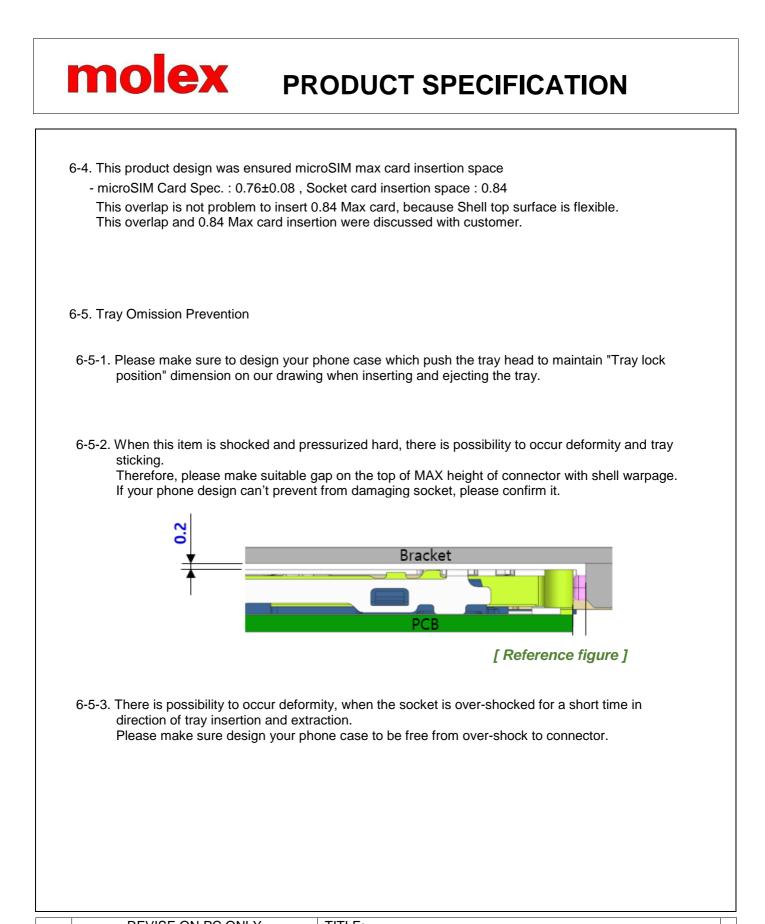
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6-3. Tray mis-insertion protection

-. This product prevents mis-insertion of the tray at the user's gentle force.

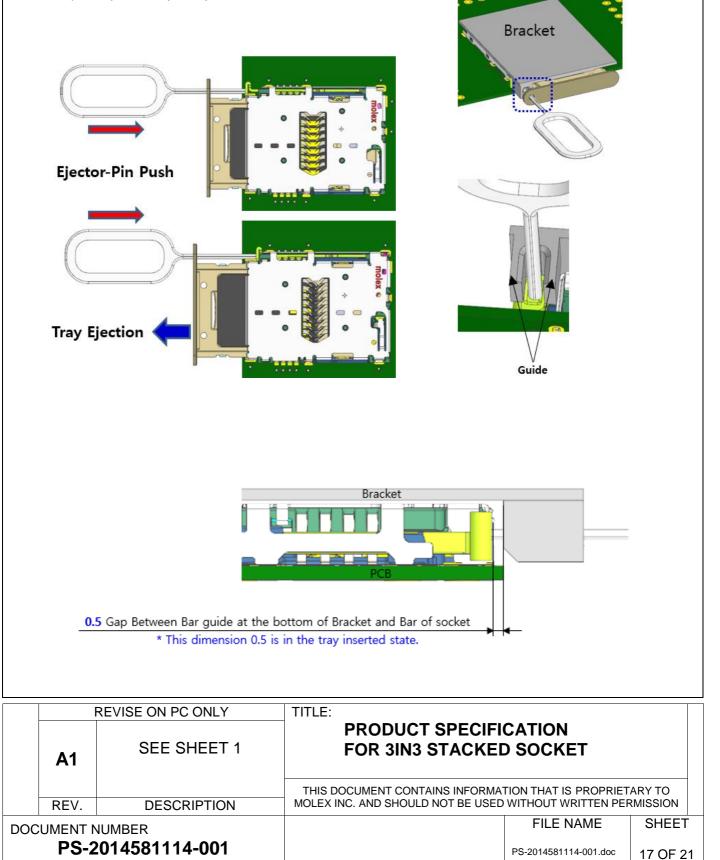


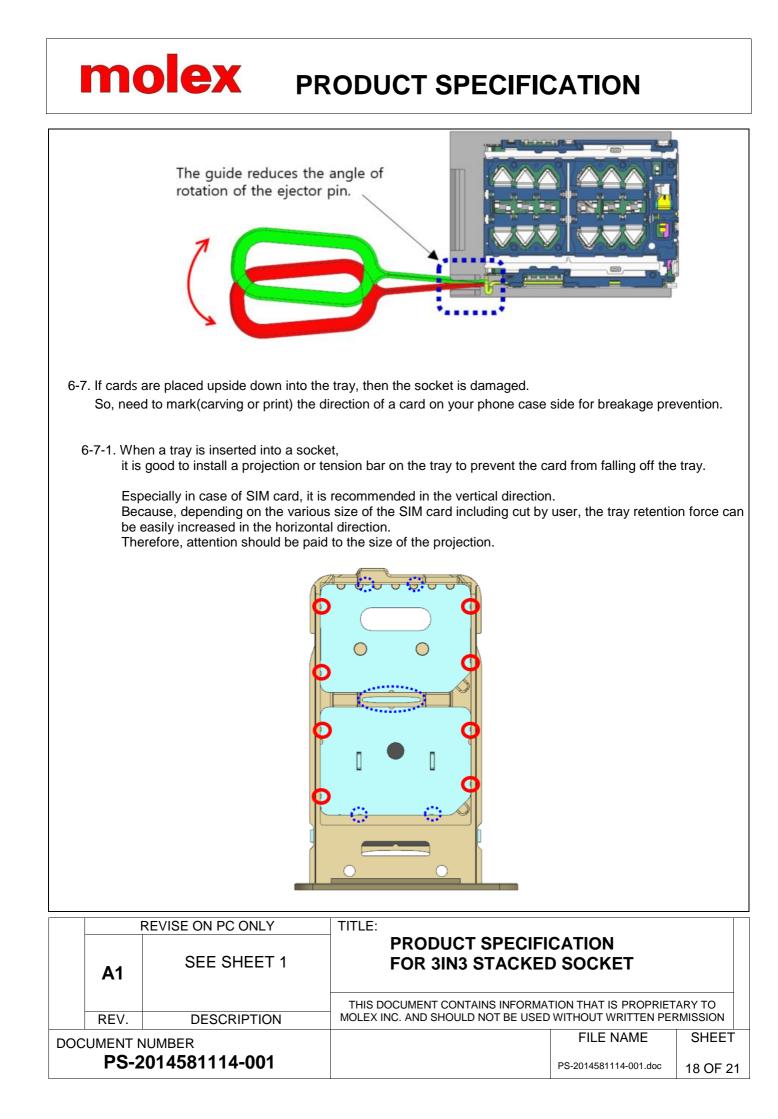


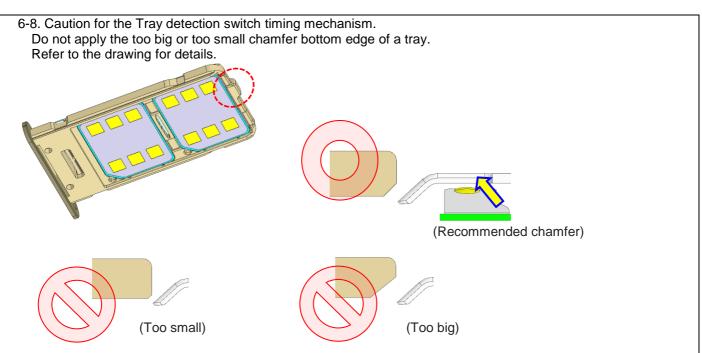
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6-6. Tray Ejection

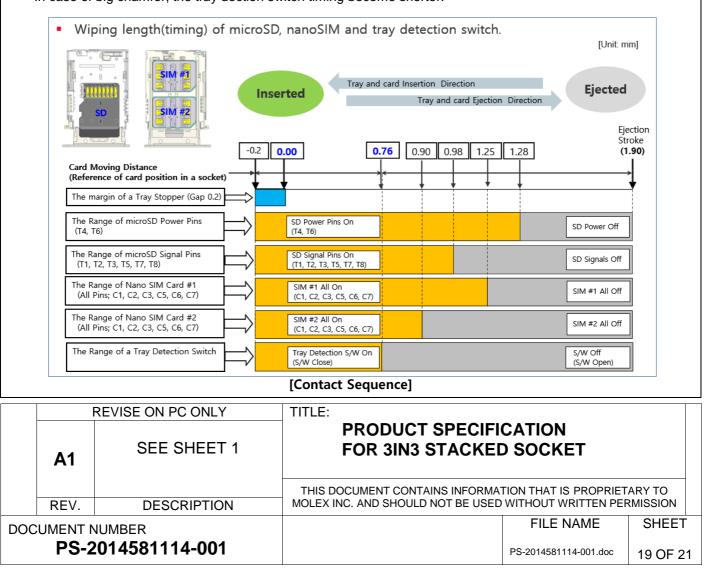
Please set up the guide surround of Ejector Pin. And reduce the space between inner surface of set case and Eject-bar of socket, it helps to eject a Tray easily.







 ※ If the chamber at edge of a tray and contact pad on SIM cards are small, the sequence of contacts may be reversed. So, software error may occur in the application(set). In case of big chamfer, the tray dection switch timing become shorter.



MOIOX PRODUCT SPECIFICATION 6-9 Please, Check the pattern prohibition(no via / no trace) on recommended PCB layout drawing. [End tip of SIM Contact terminals just gentle touch on PCB] 7.0 Etc. This product has been considered for trays that are inserted from various angles. However, round or chamfer shape is essential for the head of the tray. s(Mises) 812 046 0 1254 **REVISE ON PC ONLY** TITLE: PRODUCT SPECIFICATION

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If tray mis insertion in extreme case, it could be damaged at the Contact terminal as following.

